



AG 2881
PATENT
Docket No.: 29273/559
IFW

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

APPLICANTS: Yuko Iwabuchi et al.
APPLICATION NO.: 10/083,481
FILED: February 27, 2002
FOR: METHOD AND APPARATUS OF AN INSPECTION SYSTEM
USING AN ELECTRON BEAM
ART UNIT: 2881
EXAMINER: Jack Berman

COMMISSIONER FOR PATENTS
P. O. Box 1450
Alexandria, VA 22313-1450

RESPONSE TO OFFICE ACTION

S I R:

In response to the October 8, 2004 Office Action, Applicants submit this response.